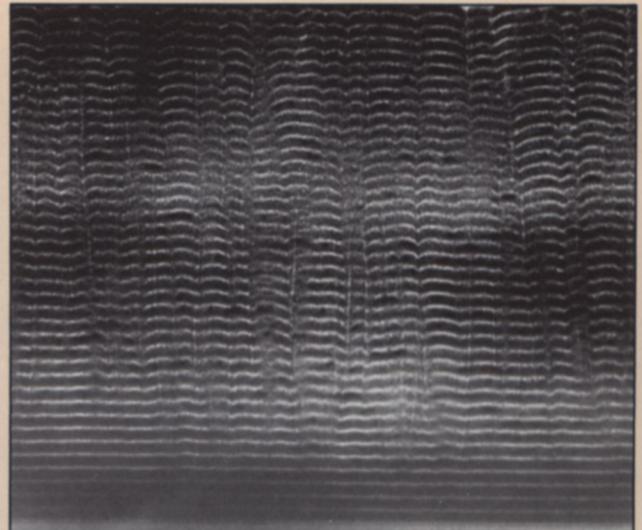
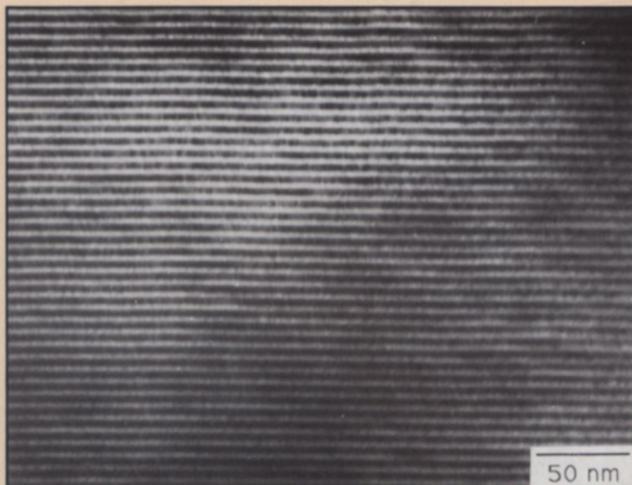
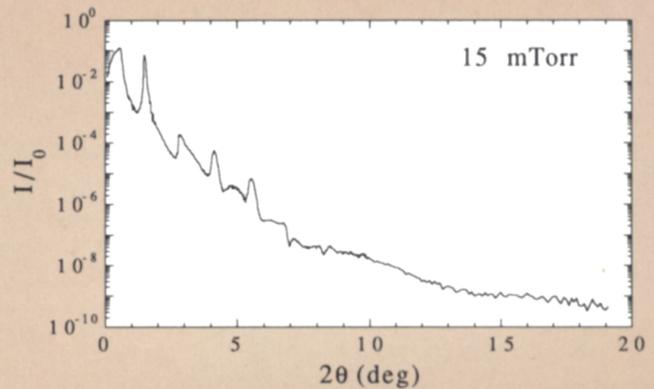
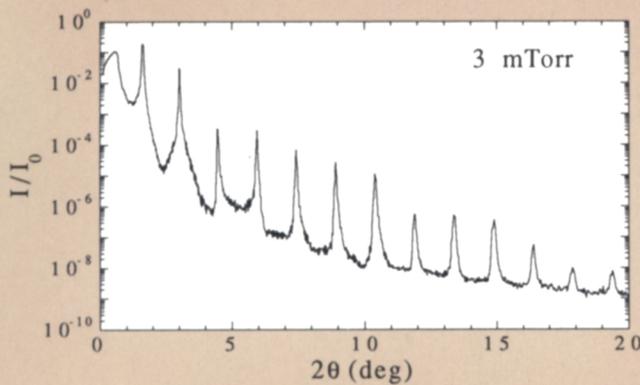




Quantitative Analysis of Thin Films

Part I



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QUANTITATIVE ANALYSIS OF THIN FILMS

20 Quantitative Structural and Chemical Analysis of Thin Films Part I

Y. Bruynseraede and I.K. Schuller,
Guest Editors

24 Microscopic Properties of Thin Films: Learning About Point Defects

A. Ourmazd, M. Scheffler,
M. Heinemann, and J.-L. Rouviere

33 Quantitative X-Ray Diffraction From Superlattices

E.E. Fullerton, I.K. Schuller, and
Y. Bruynseraede

39 Quantitative Auger and XPS Analysis of Thin Films

J.M. Slaughter, W. Weber,
G. Güntherodt, and C.M. Falco

MRS NEWS

46 Nominations Due for 1993 MRS Spring Meeting Graduate Student Awards

DEPARTMENTS

5 Letter from the President

7 Letters to the Editor

8 Resources

9 Research/Researchers

15 From Washington

18 Editor's Choice

46 Section News

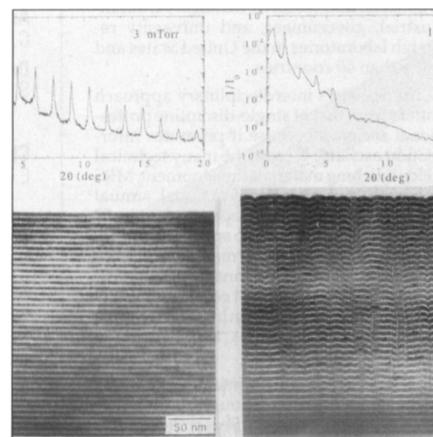
46 Advertisers in This Issue

47 Education Exchange

49 Historical Note

51 Book Reviews

53 Classified



ON THE COVER: Low-angle x-ray diffraction spectra and transmission electron microscopy image of $[\text{Nb}(35 \text{ \AA})/\text{Si}(25 \text{ \AA})]_{40}$ superlattices sputtered in an Ar pressure of 3 mTorr (left panels) and 15 mTorr (right panels). For more information on quantitative x-ray diffraction from superlattices, see the article by E.E. Fullerton et al., starting on page 33.

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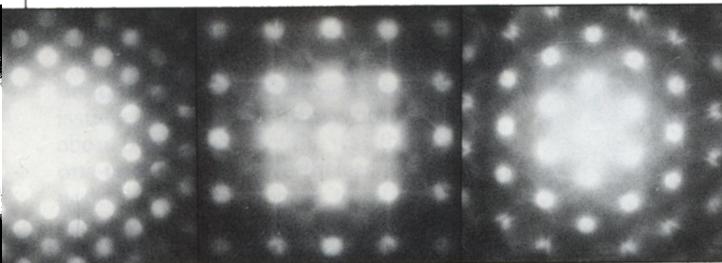
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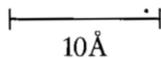
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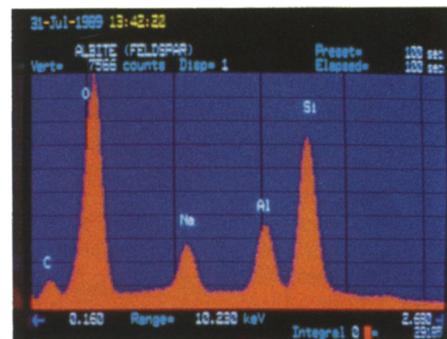
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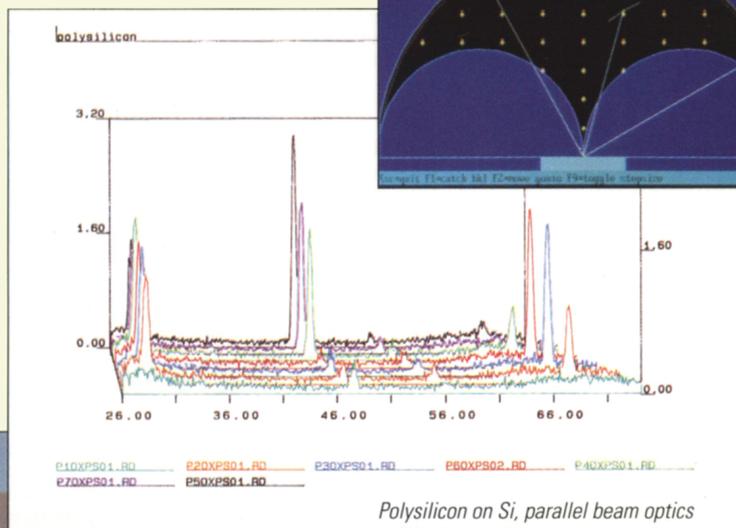
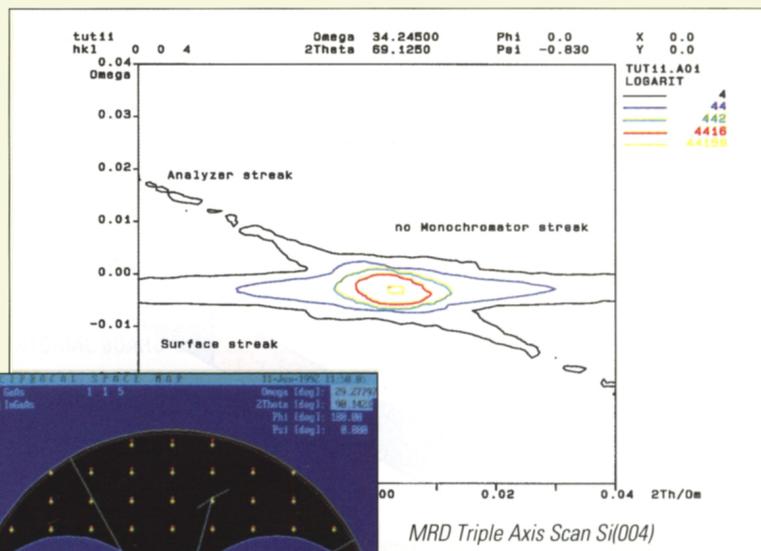
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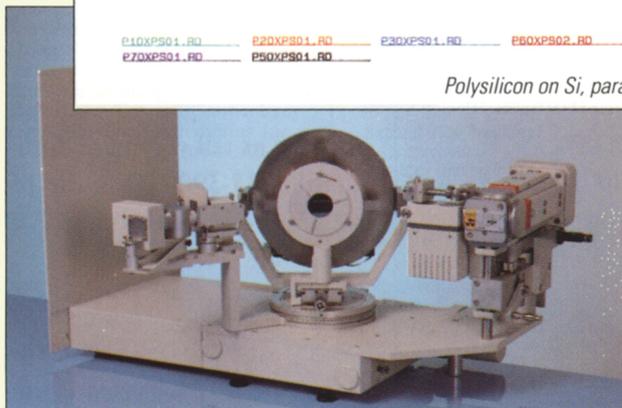
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